

Peter Milde

List of Publications by Year in descending order

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25
papers

1,559
citations

567281

15
h-index

580821

25
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docs citations

25
times ranked

2318
citing authors

#	ARTICLE	IF	CITATIONS
1	Critical sample aspect ratio and magnetic field dependence for antiskyrmion formation in $\text{Mn}_{1.4}\text{Pt}$ single crystals. <i>Physical Review B</i> , 2021, 103, .		
2	Out-of-equilibrium optomechanical resonance self-excitation. <i>Journal of Applied Physics</i> , 2021, 130, 035303.	2.5	1
3	Field-induced reorientation of helimagnetic order in $\text{Cu}_{2}\text{OSeO}_{3}$ probed by magnetic force microscopy. <i>Physical Review B</i> , 2020, 102, .	3.2	11
4	Macroscopic manifestation of domain-wall magnetism and magnetoelectric effect in a Néel-type skyrmion host. <i>Npj Quantum Materials</i> , 2020, 5, .	5.2	20
5	Anisotropic fractal magnetic domain pattern in bulk $\text{Mn}_{1.4}\text{Pt}$. <i>Physical Review B</i> , 2020, 102, .	3.2	11
6	Correlating the Nanoscale Structural, Magnetic, and Magneto-Transport Properties in SrRuO_{3} -Based Perovskite Thin Films: Implications for Oxide Skyrmion Devices. <i>ACS Applied Nano Materials</i> , 2020, 3, 1182-1190.	5.0	26
7	Surface pinning and triggered unwinding of skyrmions in a cubic chiral magnet. <i>Physical Review B</i> , 2019, 100, .	3.2	2
8	Architecture of nanoscale ferroelectric domains in $\text{GaMo}_{4}\text{S}_{8}$. <i>Journal of Physics Condensed Matter</i> , 2018, 30, 445402.	1.8	17
9	Characteristics of ferroelectric-ferroelastic domains in Néel-type skyrmion host $\text{GaV}_{4}\text{S}_{8}$. <i>Scientific Reports</i> , 2017, 7, 44663.	3.3	41
10	Multidomain Skyrmion Lattice State in $\text{Cu}_{2}\text{OSeO}_{3}$. <i>Nano Letters</i> , 2016, 16, 3285-3291.	9.1	75
11	Heuristic Description of Magnetoelectricity of $\text{Cu}_{2}\text{OSeO}_{3}$. <i>Nano Letters</i> , 2016, 16, 5612-5618.	9.1	18
12	Tracking speed bumps in organic field-effect transistors via pump-probe Kelvin-probe force microscopy. <i>Journal of Applied Physics</i> , 2015, 118, .	2.5	19
13	Pump-probe Kelvin-probe force microscopy: Principle of operation and resolution limits. <i>Journal of Applied Physics</i> , 2015, 118, .	2.5	43
14	Néel-type skyrmion lattice with confined orientation in the polar magnetic semiconductor $\text{GaV}_{4}\text{S}_{8}$. <i>Nature Materials</i> , 2015, 14, 1116-1122.	27.5	523
15	Electronic Properties of Isosymmetric Phase Boundaries in Highly Strained $\text{Ca}\delta$ -Doped BiFeO_{3} . <i>Advanced Materials</i> , 2014, 26, 4376-4380.	21.0	66
16	Epitaxial Growth of Pentacene on Alkali Halide Surfaces Studied by Kelvin Probe Force Microscopy. <i>ACS Nano</i> , 2014, 8, 3294-3301.	14.6	22
17	Unwinding of a Skyrmion Lattice by Magnetic Monopoles. <i>Science</i> , 2013, 340, 1076-1080.	12.6	468
18	Probing the local surface potential and quantum capacitance in single and multi-layer graphene. <i>Applied Physics Letters</i> , 2013, 103, .	3.3	13

#	ARTICLE	IF	CITATIONS
19	In situ self-assembled organic interface layers for the controlled growth of oligothiophene thin films on ferroelectric Pb(Zr _{0.2} Ti _{0.8})O ₃ . Journal of Chemical Physics, 2013, 139, 214702.	3.0	1
20	Transport and noise in organic field-effect devices. Physical Review B, 2009, 79, .	3.2	6
21	The effective quality factor at low temperatures in dynamic force microscopes with Fabry-Pérot interferometer detection. Applied Physics Letters, 2009, 94, .	3.3	31
22	Probing polarization and dielectric function of molecules with higher order harmonics in scattering near-field scanning optical microscopy. Journal of Applied Physics, 2009, 106, 114307.	2.5	12
23	Ferroelectric Lithography: Bottom-up Assembly and Electrical Performance of a Single Metallic Nanowire. Nano Letters, 2009, 9, 763-768.	9.1	60
24	The Effect of Molecular Orientation on the Potential of Porphyrin-Metal Contacts. Nano Letters, 2008, 8, 110-113.	9.1	53
25	Interface dipole formation of different ZnPcCl ₈ phases on Ag(111) observed by Kelvin probe force microscopy. Nanotechnology, 2008, 19, 305501.	2.6	16